Notice	of References	Cited
--------	---------------	-------

	Application/Control No.	Applicant(s)/Pater	nt Under
	10/802,927	Reexamination NAKANO ET AL.	
	Examiner	Art Unit	
1	JASON K. GEE	2134	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0190868	09-2004	Nakano et al.	386/094
*	В	US-2004/0003274	01-2004	Strom et al.	713/193
*	С	US-2003/0012098	01-2003	Sako et al.	369/47.12
*	D	US-2002/0015494	02-2002	Nagai et al.	380/201
*	Е	US-2003/0051153	03-2003	Andreaux et al.	713/200
	F	US-			
	G	US-		-	
	Н	US-		-	
	Т	US-			
	J	US-			
	к	US-			
	٦	US-			
	м	US-			

EODEIGN DATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q		1			
	R					
	s					
	т					

NON-PATENT DOCUMENTS

*	* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
-		include as applicable. Adulor, The Date, Publisher, Edition of Volume, Pertinent Pages)			
	U				
	٧				
	w				
	"				
-					
	x				

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.